

VLSI / SOC Testing

Lecture 13

1. Testing Acyclic Sequential Circuits

- Transform acyclic sequential circuit to a balanced combinational circuit
 \mapsto targeting some single faults may become multiple-faults
- Apply only combinational ATPG to get test vectors
- Transform vector to test sequence

2. Balanced Model (BM) of a circuit:

- In a balanced circuit, all signal paths between any 2 nodes have the same number of FFs
- Internally balanced: a balanced circuit where all node-pairs except those involving PIs are balanced
- Strongly balanced: more strict than balanced, in which all reachable paths from an internal node to all PIs have the same sequential depth

3. Balanced Model Generation:

- Step 1: Compute the weight of each PO to be the maximum sequential depth from any PI to the target PO
- Step 2: For each PO, compute the weights of all gates within its cone, duplicate and split whenever necessary

Example 1:

4. Issues in balanced model:

- Most sequential circuits are not balanced
- Duplication-and-split may become expensive
- Some faults become multiple-stuck-at-faults
- Positive: combinational ATPG generally less expensive than sequential ATPG

5. Simulation-Based Sequential ATPG

- Avoids backtracing and backtracking
- Simplest: (weighted) random TG

6. CONTEST: 3 phases

- phase 1: initialize fault-free circuit (no X's in FFs) by guided random walk
 - ↳ generate a set of vectors, pick the best, where
 - ↳ cost function = # FF's initialized
 - ↳ repeat till all FFs specified
 - ↳ Then, drop all detected faults by the initialization sequence

- phase 2: concurrent fault detection
 - ↳ let current state be s_f
 - ↳ generate a set of vectors, pick the best, where
 - ↳ cost function = # additional faults detected from s_f
 - ↳ repeat till remaining faults < threshold
- phase 3: single fault target
 - ↳ pick one fault at a time from remaining faults
 - ↳ generate a set of vectors, pick the best, where
 - ↳ cost function = $K \times$ activation + propagation
 - ↳ repeat till remaining faults < another threshold

7. GA-Test:

- Similar to CONTEST, except now use GA to optimize/find best vector
- No single target fault phase (only phases 1 and 2)
- Instead of adding 1 vector at a time, individuals consist of sequences
- GA individual:

8. Define: *distinguishing sequence*: a sequence, when applied, can distinguish 2 or more states by producing different output sequences

9. DIGATE

- Power of distinguishing sequences: if it can distinguish a large set of states from another, it is very powerful
- Dist. seqs learned by the ATPG at run-time. For each FF, store up to 5 dist. seqs.
- Application to ATPG: when a fault is activated to one or more FFs, propagation of the fault effect is similar to distinguishing the faulty machine from the fault-free machine

10. Distinguishing Sequence Learning

11. DIGATE Notes

- Fault-free and faulty circuits not exactly identical (but very similar), thus distinguishing sequence may not always work
- Instead of targeting a group of faults, target single faults
- For each fault, first activate it to a FF, then seed dist. seq. learned in the GA population to help propagate the fault effect to a PO
- Dist. seqs useless if target fault is not activated

12. Targeting fault activation

- Divide fault activation into 2 phases: (1) single time frame, (2) state justification
- Single time frame is similar to combinational GA-based ATPG, with a relaxation step to make some FFs don't-cares
- State justification: justify the required FFs

Example 2: State Relaxation

13. State Justification of the relaxed state

- Define: set/reset sequences: a sequence that sets/resets a particular FF from an all-unknown state
- Use set/reset sequences to guide GA to justify the required relaxed state

14. Problems with set/reset sequences

- set/reset sequences sets/resets the specified FF, and at the same time, may set/reset other FFs as well
 - ↳ conflicts in trying to justify a combination of FFs simultaneously

15. Pseudo-register justification

- Instead of set/reset sequences for individual FFs, use sequences that sets a group of FFs to a specific value

16. STRATEGATE: state-traversal based

- treat entire state instead of partitioning the state
- find similar states visited before, and use those sequences to justify the desired target state
- data structures:

17. Genetic engineering partial solutions to get the target state

18. Logic-Simulation Based Sequential ATPG

- Observation: effective traversal of circuit state space helps to detect more faults
- Thus, using only logic simulation, traverse as many states as possible
- problem: fault coverage plateaus early. Addition of arbitrary new states may not be helpful.
↳ need to differentiate new states

19. Differentiation of new states